## Notice of References Cited

Application/Control No.

09/942,478

Applicant(s)/Patent Under Reexamination MARTINS, FERNANDO

Examiner

John B Strege

Applicant(s)/Patent Under Reexamination MARTINS, FERNANDO

Art Unit
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# U.S. PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name         | Classification |
|---|---|--------------------------------------------------|-----------------|--------------|----------------|
|   | Α | US-6,639,596                                     | 10-2003         | Shum et al.  | 345/427        |
|   | В | US-6,665,003                                     | 12-2003         | Peleg et al. | 348/36         |
|   | С | US-                                              |                 |              |                |
|   | D | US-                                              |                 |              |                |
|   | Е | US-                                              |                 |              |                |
|   | F | US-                                              |                 |              |                |
|   | G | US-                                              |                 |              |                |
|   | Н | US-                                              |                 |              |                |
|   | 1 | US-                                              |                 |              |                |
|   | J | US-                                              |                 |              |                |
|   | К | US-                                              |                 |              |                |
|   | L | US-                                              |                 |              |                |
|   | М | US-                                              |                 |              |                |

### **FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
|   | N |                                                  |                 |         |      |                |
|   | 0 |                                                  |                 |         |      |                |
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|   | Q |                                                  |                 |         |      |                |
|   | R |                                                  |                 |         |      |                |
|   | S |                                                  |                 |         |      |                |
|   | Т |                                                  |                 |         |      |                |

## **NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)                                                         |
|---|---|---------------------------------------------------------------------------------------------------------------------------------------------------|
|   | U | Peleg et al., Stereo Panorama with a Single Camera, June 1999, Computer Vision and Pattern Recognition, Competer Society Conference, pgs. 395-401 |
|   | ٧ | Shum et al., Omnivergent Stereo, September 1999, Proceeding of IEEE International Conference, pages 22-29                                         |
|   | w |                                                                                                                                                   |
|   | х |                                                                                                                                                   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.